


TiN-FORT

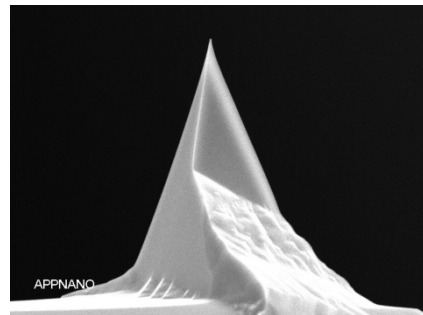
TiN-FORT probes are conducting and wear resistant primarily designed for Electrical AFM applications. These probes are compatible with most commercially available SPMs.

The applications include :

- Electrical Force Microscopy (EFM)

Kelvin Probe Force Microscopy 

- Conductive AFM (C-AFM)
- Piezoresponse Force Microscopy (PFM)
- Scanning Spreading Resistance Microscopy (SSRM) on polymer samples



Tip Specifications

- **Coating:** TiN (50 nm)
- **Material:** Silicon
- **Shape:** Tetrahedral
- **Height (µm):** 14-16
- **ROC (nm) :** 30

Cantilever Specifications

Material	: Silicon
Shape	: Rectangular
Reflex coating	: Al (50 nm)

Parameter	Nominal	Min	Max
k (N/m)	1.6	0.6	3.7
f (kHz)	61.0	43.0	81.0
Length (µm)	225.0	215.0	235.0
Width (µm)	27.0	22.0	32.0
Thickness (µm)	2.70	2.20	3.20